

Home | Login | Logout | Access Information | Ale

## Welcome United States Patent and Trademark Office

İ	Welcome United States Patent and Trademark Office						
•		BROWSE	:	SEARCH	IEEE	XPLORE GUIDE	
			ding order.				<b>⊠</b> e-mail
Modify	Modify Search						
((силе	((current and leakage and scan and chain ) <in>metadata)</in>					(Search)	
□с	heck to	search only within	this results set				
Display	y Forma	at: 🜀 Ci	itation C	Citation & Abstrac	#		
viev	w sele	cted items	Select All Des	select All			
		=			y Input ve	ctor control	
	Ve	ery Large Scale Inte	egration (VLSI)	Systems, IEEE Tra	ansactions	<u>on</u>	
			•	• •			
	•	•			EEE JNL		
			-				
	2. Le	akage current red	luction in sequ	ential circuits by	modifying	the scan chains	
-					ntomotiono	d Symposium on	
			-	ceedings, Fouthin	Melliariolia	i Symposium on	
	Diç	gital Object Identifie	er 10.1109/ISQE	ED.2003.1194708			
				B) IEEE CNF			
П	3. A	novel scan chain	diagnostics te	chnique based or	ı light emi:	ssion from leakage	current
		-	- · · · · ·		ational		
			_	. 11 0 2004. Interne	analiai		
	Diç	gital Object Identifie	er 10.1109/TES	T.2004.1386946			
				B) IEEE CNF			
	4. A	practical built-in c	urrent sensor:	for I <sub>DDQ</sub> testing			
		•					
				B) IEEE CNF		,	
	5. Co	ounting and integr	ating readout f	for direct convers	sion X-ray	Imaging concept, i	realization aı
	me	easurements					
	Modify ((current) C Display	Modify Search  ((current and le  Check to  Display Forma  View Sele  1. Le  Ab  Ve  Vo  Di  Ab  Bid  3. A i  So  Le  20  Di  Ab  Ri  Ab  Ab  Ab  Ab  Ab  Ab  Ab  Ab  Ab  A	BROWSE  d chain ) <in>metadata)"  page, sorted by Relevance in Descen  Modify Search  ((current and leakage and scan and  Check to search only within  Display Format:  1. Leakage current rec Abdollahi, A.; Fallah, Very Large Scale Inte Volume 12, Issue 2, Digital Object Identific AbstractPlus   Refere Rights and Permissio  2. Leakage current rec Abdollahi, A.; Fallah, Quality Electronic De 24-26 March 2003 Pa Digital Object Identific AbstractPlus   Full Te Rights and Permissio  3. A novel scan chain Song, P.; Stellari, F.; Test Conference. 200 2004 Page(s):140 - 1 Digital Object Identific AbstractPlus   Full Te Rights and Permissio  4. A practical built-in c Hoki Kim; Walker, D.I Test Conference. 200 30 Oct1 Nov. 2001 R Digital Object Identific AbstractPlus   Full Te Rights and Permissio  5. Counting and Integr measurements</in>	BROWSE  d chain   <   Nometadata   Chain   <   Nometadata    page, sorted by Relevance in Descending order.    Modify Search	BROWSE SEARCH  d chain ] <in>   In   In   In   In   In   In   In   In</in>	BROWSE SEARCH IEEE  d chain   <in>   Select All Deselect All   Check to search only within this results set   Display Format:</in>	d chain   <in>page, sorted by Relevance in Descending order.  Modify Search  ((current and leakage and scan and chain  <in>mentadata)  Check to search only within this results set  Display Format:  Citation  Citation &amp; Abstract  1. Leakage current reduction in CMOS VLSI circuits by input vector control Abdollahi, A.; Fallah, F.; Pedram, M.;  Very Large Scale integration (VLSI) Systems. IEEE Transactions on Volume 12, Issue 2, Feb. 2004 Page(s):140 - 154  Digital Object Identifier 10.1109/TVLSI.2003.821546  AbstractPlus   References   Full Text: PDF(560 KB)   IEEE JNL. Rights and Permissions  2. Leakage current reduction in sequential circuits by modifying the scan chains Abdollahi, A.; Fallah, F.; Pedram, M.;  Quality Electronic Design. 2003. Proceedings. Fourth International Symposium on 24-26 March 2003 Page(s):49 - 54  Digital Object Identifier 10.1109/RQED.2003.1194708  AbstractPlus   Full Text: PDE(243 KB)   IEEE CNF. Rights and Permissions  3. A novel scan chain disgnostics technique based on light emission from leakage Song, P.; Stellari, F.; Xia, T.; Weger, A.J.;  Test Conference. 2004. Proceedings. ITC 2004. International 2004 Page(s):140 - 147  Digital Object Identifier 10.1109/TEST.2004. 1386946  AbstractPlus   Full Text: PDF(630 KB)   IEEE CNF. Rights and Permissions  4. A practical built-in current sensor for Ipoq testing Hok Kim; Walker, D.M.H.; Colby, D.;  Test Conference. 2001. Proceedings. International 30 Oct1 Nov. 2001 Page(s):405 - 414  Digital Object Identifier 10.1109/TEST.2001.966657  AbstractPlus   Full Text: PDE(954 KB)   IEEE CNF. Rights and Permissions  5. Counting and Integrating readout for direct conversion X-ray Imaging concept, No. 2001. Proceedings. International 2001. Proceedings. Inte</in></in>

Nuclear Science Symposium Conference Record, 2005 IEEE

Volume 5, 23-29 Oct. 2005 Page(s):2761 - 2765

M.; Rutten, W.;